ELECTRON DIFFRACTION IN THE
ELECTRON MICROSCOPE

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2

ELECTRON DIFFRACTION IN THE ELECTRON MICROSCOPE

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PREFACE

This is the second of a series of monographs on electron microscopy aimed at users of the equipment. They are written both as texts and sources of reference emphasising the applications of electron microscopy to the characterisation of materials.

In some places the author has referred the reader to material appearing in other monographs of the series. The following title has already been published:

1. *The Operation and Calibration of the Electron Microscope*

and the titles in preparation are:

3. *Interpretation of Transmission Electron Micrographs*

4. *Typical Electron Microscope Investigations*

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